

RELIABILITY CENTER FOR ELECTRONIC COMPONENTS OF JAPAN RCJ

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Dear Professor M. D. Ker,

The RCJ EOS/ESD/EMC Symposium program committee is very pleased to invite you as a keynote speaker to the RCJ EOS/ESD/EMC Symposium 2010.

20th 2010 RCJ EOS/ESD/EMC Symposium will be held in 21 – 22 October 2010 at Otaku Sangyo Plaza (Tokyo) that is the same place of last year's symposium. Your paper will be scheduled to present on the afternoon of 21 October 2010.

RCJ EOS/ESD/EMC Symposium has close contact with ESD Association and Europe ESD community, and many people from USA and Europe has been attended. We are pleased to invite you our Symposium, and hope to expand cooperation between Asian ESD communities.

Your paper will be presented in English, but we regretfully inform you that in other sessions, papers will be presented in Japanese and the symposium proceedings are also written in Japanese.

We would also like to ask you that travel expense and accommodation cost should be paid in your own expense except registration fee.

Best Regards,



Noboru Shiono (Secretary of RCJ Reliability Symposium)

On-Chip Solution in CMOS Integrated Circuits for System-Level ESD Protection

Prof. Ming-Dou Ker (柯明道教授), IEEE FELLOW

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Outline

- Component-Level ESD vs. System-Level ESD
- Some Examples of System-Level ESD Protection in CMOS Chips
- On-Chip Transient-to-Digital Converter
- Summary